

TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

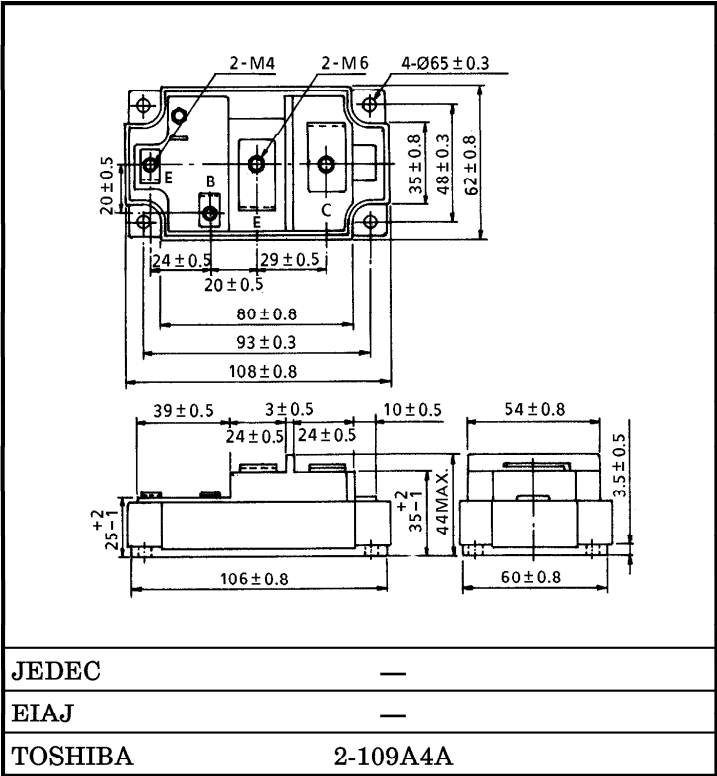
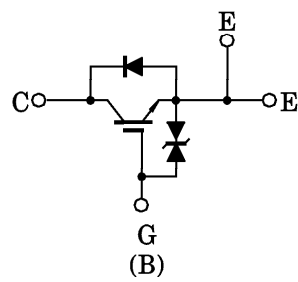
MG200Q1US41

HIGH POWER SWITCHING APPLICATIONS
MOTOR CONTROL APPLICATIONS

Unit in mm

- High Input Impedance
- High Speed : $t_f=0.5\mu s$ (Max.)
: $t_{rr}=0.5\mu s$ (Max.)
- Low Saturation Voltage
: $V_{CE(sat)}=4.0V$ (Max.)
- Enhancement-Mode
- The Electrodes are Isolated from Case.

EQUIVALENT CIRCUIT



Weight : 465g

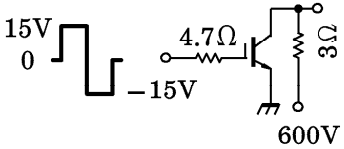
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Emitter Voltage		V_{CES}	1200	V
Gate-Emitter Voltage		V_{GES}	± 20	V
Collector Current	DC	I_C	200	A
	1ms	I_{CP}	400	
Forward Current	DC	I_F	200	A
	1ms	I_{FM}	400	
Collector Power Dissipation (Tc = 25°C)		P_C	1400	W
Junction Temperature		T_j	150	°C
Storage Temperature Range		T_{stg}	− 40~125	°C
Isolation Voltage		V_{Isol}	2500 (AC, 1 min.)	V
Screw Torque (Terminal : M4 / M6 / Mounting)		—	2 / 3 / 3	N·m

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GES}	$V_{GE} = \pm 20V, V_{CE} = 0$	—	—	± 40	μA
Collector Cut-off Current		I_{CES}	$V_{CE} = 1200V, V_{GE} = 0$	—	—	4.0	mA
Gate-Emitter Cut-off Voltage		$V_{GE} (OFF)$	$I_C = 200mA, V_{CE} = 5V$	3.0	—	6.0	V
Collector-Emitter Saturation Voltage		$V_{CE} (sat)$	$I_C = 200A, V_{GE} = 15V$	—	3.0	4.0	V
Input Capacitance		C_{ies}	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$	—	24000	—	pF
Switching Time	Rise Time	t_r		—	0.3	0.6	μs
	Turn-on Time	t_{on}		—	0.4	0.8	
	Fall Time	t_f		—	0.2	0.5	
	Turn-off Time	t_{off}		—	0.8	1.5	
Forward Voltage		V_F	$I_F = 200A, V_{GE} = 0$	—	2.0	3.0	V
Reverse Recovery Time		t_{rr}	$I_F = 200A, V_{GE} = -10V$ $di/dt = 300A/\mu s$	—	0.25	0.5	μs
Thermal Resistance		$R_{th(j-c)}$	Transistor	—	—	0.089	$^{\circ}C/W$
			Diode	—	—	0.25	

